


<b>INFORMATION DISCLOSURE STATEMENT TRANSMITTAL</b>  To Commissioner For Patents Enclosed herewith is a Form PTO-1449, any required copies of documents listed thereon, and any concise explanation of their relevance is indicated below per 37 CFR 1.97.	Application Number	10/562293
	Filing Date	12.22.05
	First Named Inventor	GREEN, PETER W.
	Group Art Unit	2823
	Examiner Name	N. Tobeste
	Atty. Docket Number	GB02 0136 US

U.S. PATENT DOCUMENTS					
Examiner Initials*	Cite No. <sup>1</sup>	Document Number No.-Kind Code <sup>2</sup> (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns Lines, Where Relevant Passages or Relevant Figures Appear
NT	1	US- 5 130 829	07/14/1992	SHANNON JOHN M.	
NT	2	US- 5 340 758	08/23/1994	WEI, CHING-YEU	
		US-			
		US-			
		US-			
		US-			

FOREIGN PATENT DOCUMENTS						
Examiner Initials*	Cite No. <sup>1</sup>	Document Number (ctry <sup>3</sup> -no.-kind <sup>2</sup> , if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of cited document	Pages, Columns Lines, Where Relevant Passages or Relevant Figures Appear	† <sup>4</sup>
NA	1	JP 11 004001	01/06/1999			
NA	2	WO 02/091475 A1	11/14/2002	DEANE STEVEN C. ET AL.		

NON-PATENT LITERATURE DOCUMENTS			
Examiner Initials*	Cite No. <sup>1</sup>	Include name of the author (in capital letters), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	† <sup>4</sup>
NT	1	YASUTAKA UCHIDA ET AL: "VERTICAL-TYPE AMORPHOUS-SILICON FIELD-EFFECT TRANSISTORS WITH SMALL PARASITIC ELEMENTS"; JAPANESE JOURNAL OF APPLIED PHYSICS; TOKYO, JAPAN; Sept. 9 <sup>th</sup> , 1986; pages 798-800	
NT	2	MASAKIYO MATSUMURA ET AL.: "AMORPHOUS-SILICON THIN-FILM TRANSISTORS MATCHED TO ULTRA-LARGE PANELS; MATERIALS RESEARCH SOCIETY; TOKYO, JAPAN; Vol. 467; 1997; pages 821-829	
NT	3	700 IBM TECHNICAL DISCLOSURE BULLETIN 29 (1986); OCT. No. 5; NY USA	

Examiner Signature		Date Considered	12/18/06
--------------------	---	-----------------	----------

\* EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

<sup>1</sup> Unique citation designation number. <sup>2</sup> See attached Kinds of U.S. Patent Documents. <sup>3</sup> Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). <sup>4</sup> For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the